Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/812,890	JAPP ET AL.	
Examiner	Art Unit	
Thinh T. Nguyen	2818	

SEARCHED			
Class	Subclass	Date	Examiner
257	762	10/27/2005	TTN
257	760	10/27/2005	TTN
257	703	10/28/2005	TTN
257	758	10/28/2005	ΠN
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

	DATE	EXMR
EAST	10/27/2005	TTN
EAST	10/28/2005	TTN
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